TEST REPORT

Report Reference No. ....:	RET090428002	
Date of issue.......................................:	2009-04-28	
Applicant ....:	Hope Microelectronics CO., LTD	
Address ....:	4/F, Block B3, East Industrial Area, Huaqiaochen, Shenzhen, Guangdong, China	
Test item description..........................:	FSK RF Modules	
Model/Type reference ....:	RFM01、RFM02、RFM12、RFM12B、RFM12BP、HM-T、HM-R、HM-TR series modules	
Date of receipt of test item ....:	2009-04-08	
Date(s) of performance of test...........:	2009-04-08~ 2009-04-28	
Test requested:	In accordance with the RoHS Directive 2002/95/EC, and its amendment directives	
Test method..:	With reference to IEC 62321-2007	
A)	ED-XRF	
B)		
(1) Pb	ICP-OES	
(2) Cd	ICP-OES	
(3) Hg	CV-AAS	
(4) Cr (VI)	EPA3060A , UV-VIS	
(5) PBBs 、 PBDEs	EPA3540C, GC/MS	
General remarks This report shall not be reproduced except in full, without the written approval of the testing laboratory. The test results presented in this report relate only to the item(s) tested.		
Tested by (position+printed name+signature).....:	Test Engineer Jane Li	....
Approved by (position+printed name+signature)....:	Manager Xian Wang	....
Result ....:	**Refer to next page(s)**	

Report Number: RET090428002

Applicant: Hope Microelectronics CO., LTD

Sample Code	Parts/Material Name	Pb	Hg	Cd	Cr（VI）	PBBs	PBDEs	Test Method
1	Tin silk	ND	ND	ND	ND	NA	NA	A
2	Cleanser	ND	ND	ND	ND	ND	ND	A
3	Black rubber	ND	ND	ND	ND	ND	ND	A
REC20000ABJ1	Resistance	623	ND	ND	ND	NA	NA	A
CACK0010G2J1	Capacitor	ND	ND	ND	ND	ND	ND	A
TSC000039040A	Transistor	ND	ND	ND	ND	ND	ND	A
DIC00HMC2260	Transmit/Receire switch	ND	ND	ND	ND	ND	ND	A
ICB0000RF010	IC	ND	ND	ND	ND	ND	ND	A
ICC08EB053AB	Packaging chip	ND	ND	ND	ND	ND	ND	A
ICC00MAX2320	IC	ND	ND	ND	ND	ND	ND	A
ICC0ATMEG480	IC	ND	ND	ND	ND	ND	ND	A
INCG039001J1	Terrace inductor	ND	ND	ND	ND	ND	ND	A
CRC100003A70	Quartz crystal	ND	ND	ND	ND	ND	ND	A
INCE047001J1	Wire wound chip inductor	ND	ND	ND	ND	ND	ND	A
TSC000039040B	Transistor	ND	ND	ND	ND	NA	NA	A
DIC00LL41480	Diode	227787*	ND	ND	ND	ND	ND	A
CRE100003A11-1	Quartz Crystal	ND	ND	ND	ND	NA	NA	A
CRE100003A11-2	Pin	ND	ND	ND	ND	NA	NA	A
CNEB20000010-1	Black plastic	ND	ND	ND	ND	ND	ND	B
CNEB20000010-2	Pin	ND	ND	ND	ND	NA	NA	A
ANA0000002A0-1	Red wire skin	ND	ND	ND	ND	ND	ND	A

Note：

（1） Unit : mg/kg ~ ppm

（2） NA＝Not applicable

（3） ND＝Not detected(＜MDL)

（4） (*)=Lead is exempted according to the Commission Decision 2005/747/EC

Sample Code	Parts/Material Name	Pb	Hg	Cd	Cr（VI）	PBBs	PBDEs	Test Method
ANA0000002A0-2	Copper wire	ND	ND	ND	ND	NA	NA	A
CNEI10000001-1	SMA red plastic cover	ND	ND	ND	ND	ND	ND	A
CNEI10000001-2	White plastic	ND	ND	ND	ND	ND	ND	A
CNEI10000001-3	Yellow copper nut	9729*	ND	ND	ND	NA	NA	A
PCRFM01SC2CO	PCB	ND	ND	ND	ND	ND	ND	B1*
PCORFM01C2BO	PCB	ND	ND	ND	ND	ND	ND	B2*
CAEA2207C4J1-1	Black plastic paper	ND	ND	ND	ND	ND	ND	B3*
CAEA2207C4J1-2	Black rubber ring	ND	ND	ND	ND	ND	ND	A
CAEA2207C4J1-3	Pin	ND	ND	ND	ND	NA	NA	A
CAEA2207C4J1-4	Electrolytic paper	ND	ND	ND	ND	ND	ND	A
CAEA2207C4J1-5	Aluminum shell	ND	ND	ND	ND	NA	NA	A
PA180000151	Anti-electrostatic bag	ND	ND	ND	ND	ND	ND	A

Note：

（1） Unit : mg/kg ~ ppm
（2） NA＝Not applicable
（3） ND＝Not detected(＜MDL)
（4） (*)=Lead is exempted according to the Commission Decision 2005/747/EC
（5） B1*＝Results of NO. PCRFM01SC2CO refer to test report CANEC0901411403/SGS
（6） B2*＝Results of NO. PCRFM01SC2CO refer to test report CANEC0901411403/SGS
（7） B3*＝Results of NO. CAEA2207C4J1-1 refer to test report RLSZA00006864/CTI


1


2

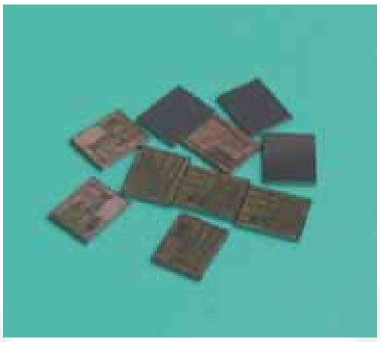

3


REC20000ABJ1


CACK0010G2J1


TSC000039040A


DIC00HMC2260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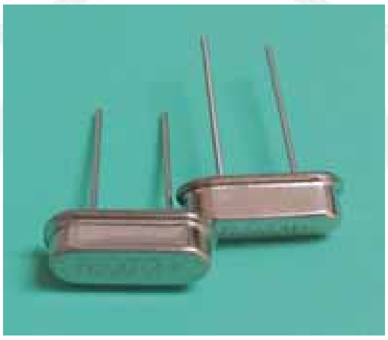
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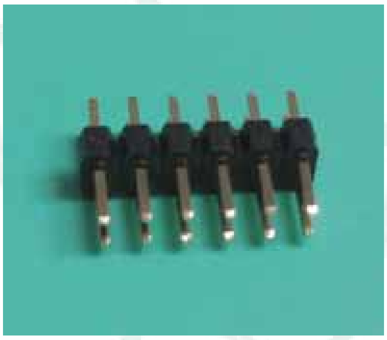
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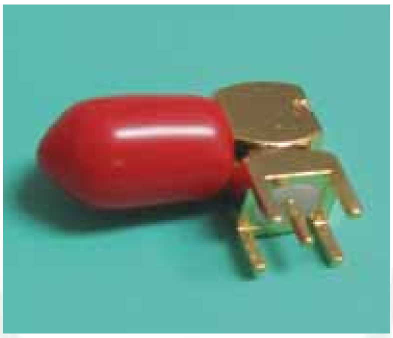
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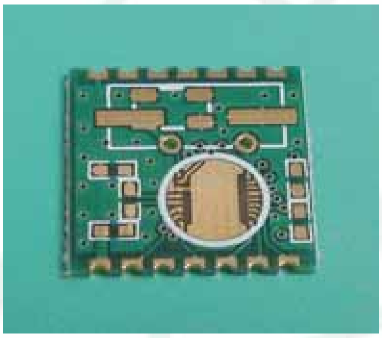
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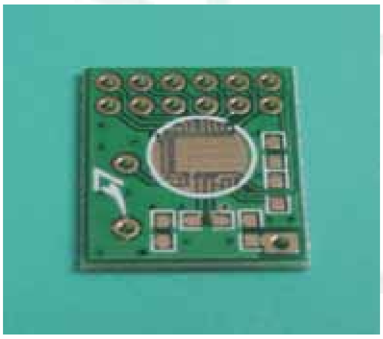
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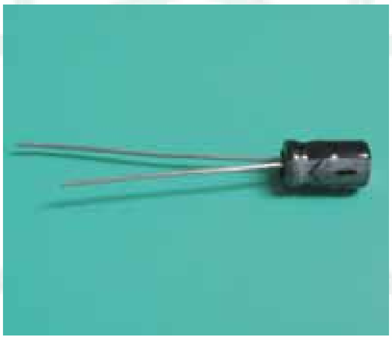
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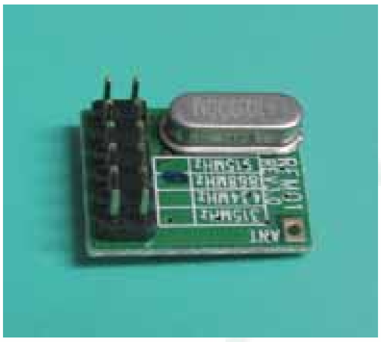
PA180000151



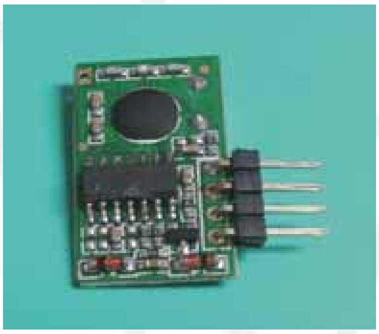
RFM01(DIP)

RFM01(SMD)

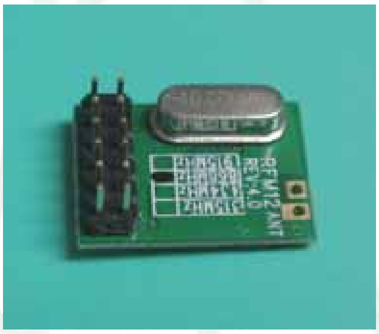
RFM12BP

RFM02(DIP)

RFM02(SMD)



HM-R



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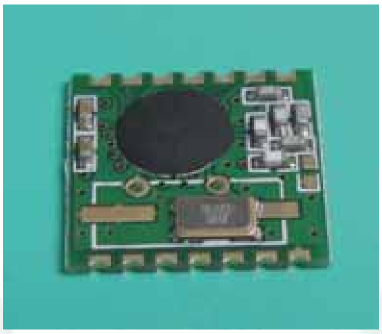

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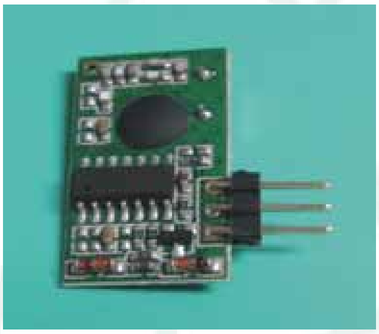

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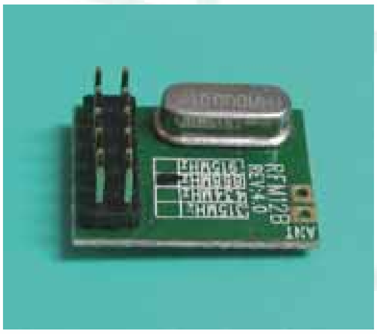
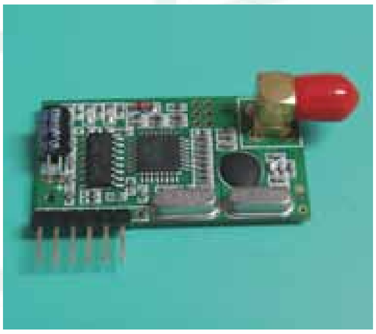


RFM12B(DIP)

RFM12B(SMD)



HM-TR